Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π–MOSIII)

2SK2847

DC-DC Converter and Motor Drive Applications

: RDS (ON) = 1.1Ω (typ.)

• High forward transfer admittance : $|Y_{fs}| = 7.0 \text{ S (typ.)}$

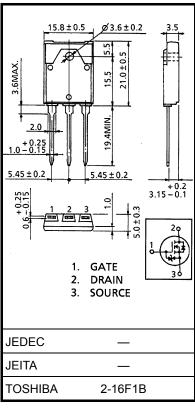
• Low leakage current : $I_{DSS} = 100 \mu A \text{ (max) (V}_{DS} = 720 \text{ V)}$

• Enhancement mode : $V_{th} = 2.0 \sim 4.0 \text{ V (Vps} = 10 \text{ V, Ip} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

• Low drain-source ON resistance

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	900	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	900	V	
Gate-source voltage		V _{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	8	Α	
	Pulse (Note 1)	I _{DP}	24	Α	
Drain power dissipatio	n (Tc = 25°C)	P _D	85	W	
Single pulse avalanche energy (Note 2)		E _{AS}	799	mJ	
Avalanche current		I _{AR}	8	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	8.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	



Weight: 5.8 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	1.47	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	41.6	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^{\circ}\text{C}$ (initial), L = 22.9 mH, $R_G = 25 \Omega$, $I_{AR} = 8 \text{ A}$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



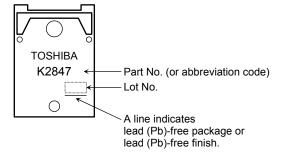
Electrical Characteristics (Ta = 25°C)

Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	irrent	I _{GSS}	V _{GS} = ±30 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V (BR) GSS	I _G = ±10 μA, V _{DS} = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 720 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	900	_	_	V
Gate threshold v	/oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 4 A	_	1.1	1.4	Ω
Forward transfer	r admittance	Y _{fs}	V _{DS} = 15 V, I _D = 4 A	3.0	7.0	_	S
Input capacitano	e	C _{iss}			2040	_	pF
Reverse transfer capacitance		C _{rss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	45	_	
Output capacitance		Coss		_	190	_	
Switching time	Rise time	t _r	$V_{GS} \stackrel{10V}{\underset{0V}{\bigvee}} \stackrel{I_{D}=4A}{\underset{R_{L}}{\bigvee}} \stackrel{V_{OUT}}{\underset{R_{L}}{\bigvee}}$	_	25	_	- ns
	Turn-on time	t _{on}		_	60	_	
	Fall time	t _f		_	20	_	
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\rm W} = 10 \mu \rm s$	_	95	_	
Total gate charg plus gate-drain)	-		_	58	_		
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$		32	_	nC
Gate-drain ("miller") Charge		Q_{gd}			26	_	

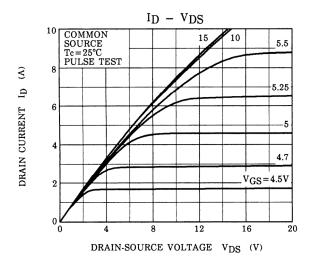
Source-Drain Ratings and Characteristics (Ta = 25°C)

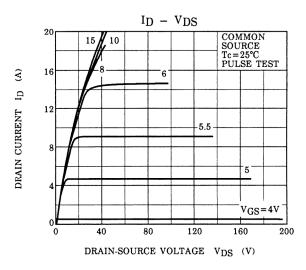
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	8	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	24	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 8 A, V _{GS} = 0 V	_	_	-1.9	V
Reverse recovery time	t _{rr}	I _{DR} = 8 A, V _{GS} = 0 V		1650	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} / dt = 100 A / μs	_	21	_	μC

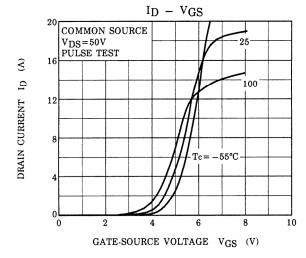
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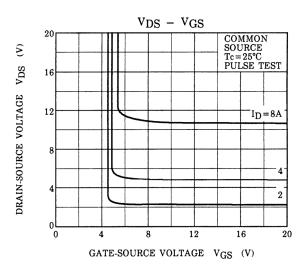


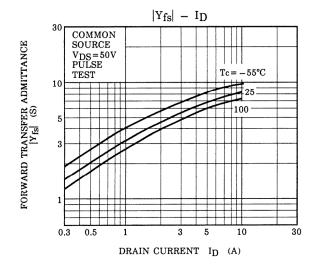
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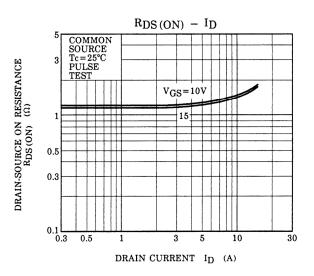


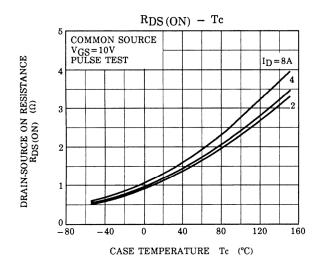


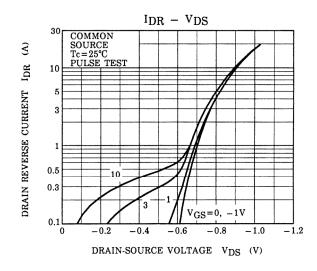


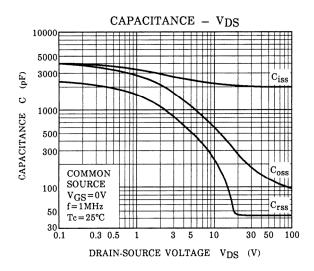


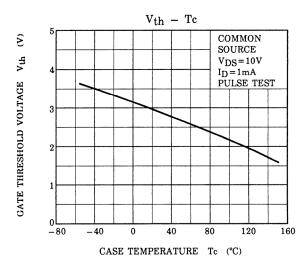


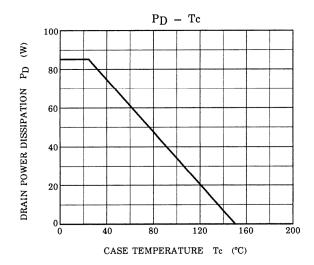


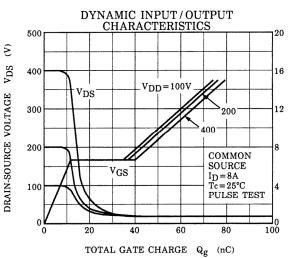




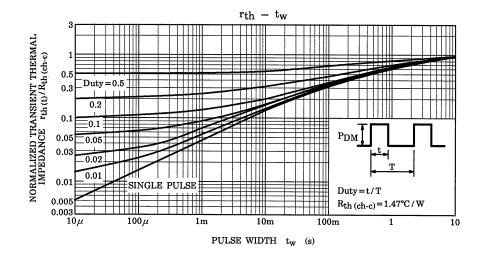


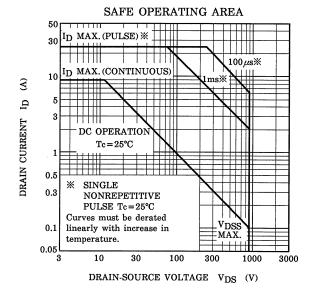


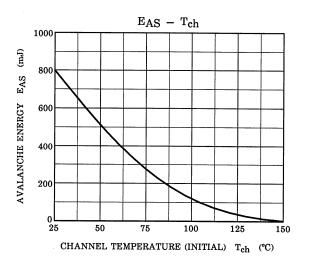


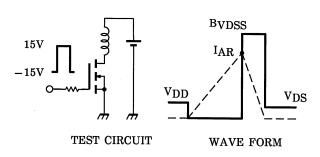


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$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 90~V,~L = 22.9~mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right) \end{aligned}$$

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